

<b>Notice of References Cited</b>	Application/Control No. 10/598,997		Applicant(s)/Patent Under Reexamination NAKAMURA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2007/0125645	06-2007	Nakamura et al.	204/298.12
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

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